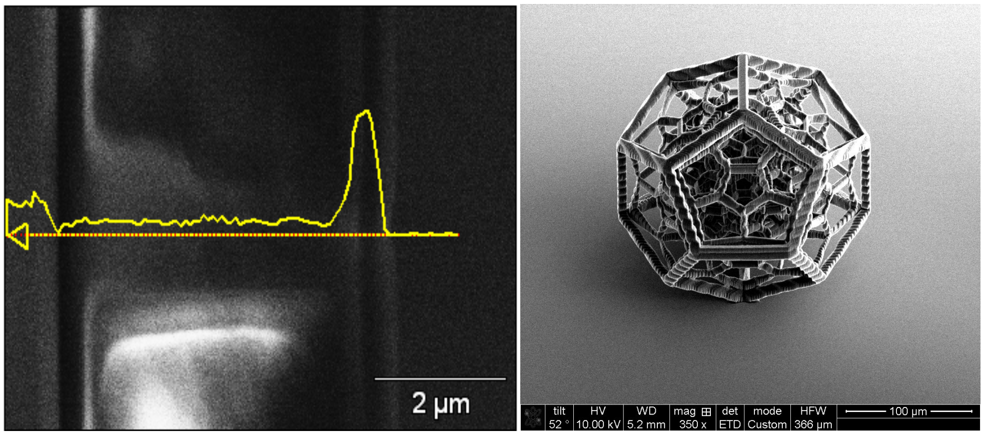

Figure 1. (Left) Cross sectional EDS data of SiS ZnO in IP-L 780. Arrow indicates position of linescan, while yellow line indicates Zn L-shell x-rays. (Right) Three dimensional ZnO infiltrated IP-L 780 structure printed using 25x objective.

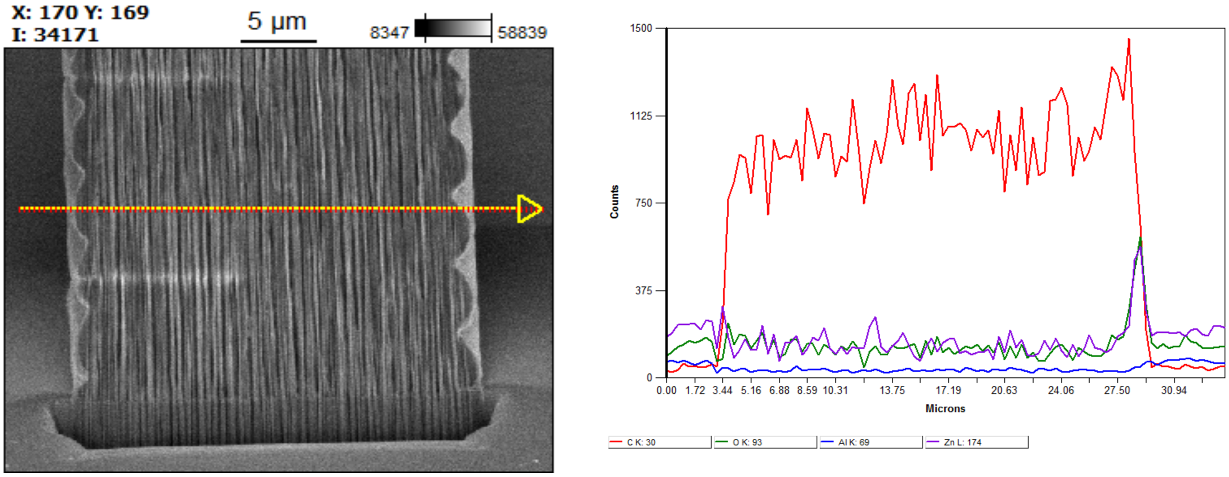

Figure 3. (Left) Focused ion beam milled SiS IP-L 780 surface with the arrow indicating the position of the linescan. (Right) EDS data with purple line indicating Zn L-shell x-rays, blue line indicating Al K-shell x-rays, green line indicating O K-shell x-rays, and red line indicating C K-shell x-rays.